

IN THE UNITED STATES RECEIVING OFFICE (RO/US) 10/523371 Designated/Elected Office (DO/EO/US)

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DT05 Rec'd PCT/PT0 0 2 FEB 2005

International Application No.:

PCT/US2004/017251

International Filing Date:

01 June 2004

Earliest Priority Date:

02 June 2003

Applicants:

Jeffrey J. Spiegelman, Daniel Alvarez, Jr., Russell J. Holmes,

and Allan Tram

Title:

METHOD FOR THE REMOVAL OF AIRBORNE MOLECULAR

CONTAMINANTS USING OXYGEN AND/OR WATER GAS MIXTURES

Date: 2 February 2005

EXPRESS MAIL LABEL NO. EV 214960082 US

INFORMATION DISCLOSURE STATEMENT

Mail Stop PCT **Commissioner for Patents** P.O. Box 1450 Alexandria, VA 22313-1450

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Sir:	
This Informati	on Disclosure Statement is submitted: under 37 CFR 1.129(a), or (First/Second submission after Final Rejection)
[X]	under 37 CFR 1.97(b), or (Within any one of the following time periods: three months of filing national application (other than a CPA) or date of entry of the national stage in an international application; or before the mailing date of a first office action on the merits in a non-provisional application, including a CPA, or a Request for Continued Examination).
[]	under 37 CFR 1.97(c) together with either: [] a Statement under 37 CFR 1.97(e), as checked below, or [] a \$180.00 fee under 37 CFR 1.17(p), or (After the 37 CFR 1.97(b) time period, but before final action or notice of allowance, whichever occurs first)
[]	under 37 CFR 1.97(d) together with: [] a Statement under 37 CFR 1.97(e), as checked below, and [] a \$180.00 fee under 37 CFR 1.17(p), or (Filed after final action or notice of allowance, whichever occurs first, but on or before payment of the issue fee)
[]	under 37 CFR 1.97(i): Applicant requests that the IDS and cited reference(s) be placed in the application filewrapper. (Filed after payment of issue fee)

Staten	<u>nent Un</u>	der 37 (CFR 1.97(e)	
[]	Each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this Information Disclosure Statement; or			
[]		in a co and, to inform individual	m of information contained in this Information Disclosure Statement was cited ommunication from a foreign patent office in a counterpart foreign application, to the knowledge of the undersigned, after making reasonable inquiry, no item of nation contained in the information disclosure statement was known to any dual designated in 37 CFR 1.56(c) more than three months prior to the filing of formation Disclosure Statement.	
Statem	nent Un	der 37 (CFR 1.704(d) (Patent Term Adjustment) Applies to original applications (other than design) filed on or after May 29, 2000	
[]	comm	unicatio unicatio	information contained in the Information Disclosure Statement was cited in a confrom a foreign patent office in a counterpart application and this on was not received by any individual designated in § 1.56(c) more than thirty he filing of the Information Disclosure Statement.	
[X]	Enclos	sed here	with is form PTO-1449:	
	[X]	Copies	s of the cited references are enclosed.	
		[X]	Copies of issued U.S. patents and published U.S. applications are not required and are not being provided.	
	[]	U.S. A	s of the cited references are enclosed except those entered in prior application, application No. [], to which priority under 35 U.S.C. 120 is claimed. [The application contains copies of the cited references.]	
	[]	The lis	sted references were cited in the enclosed International Search Report in a repart foreign application.	
	[X]	The "c	oncise explanation" requirement (non-English references) for reference AN 37 CFR 1.98(a)(3) is satisfied by:	
		[]	the explanation provided on the attached sheet.	
		[]	the explanation provided in the Specification.	
		[]	submission of the enclosed International Search Report.	
		[]	submission of the enclosed English-language version of a foreign Search Report and/or foreign Office Action.	

 $[\ X\]$ the enclosed English language abstract.

[]	Appl	licant requests that the following	non-published pending appli-	cations be considered:	
Examiner's Initials					
		U.S. Patent Application No. [], by [inventor(s)], filed [], Docket No.: [
		U.S. Patent Application No. [], by [inventor(s)], filed [], Docket No.: [
		U.S. Patent Application No. [], by [inventor(s)], filed [], Docket No.: [
		Examiner	Date	_	
	[]	A copy of each above-cited ap except any application filed on the PTO's Image File Wrappe	n or after June 30, 2003, which	ch has been scanned in	to
	[]	A copy of each above-cited apexcept those entered in prior a priority under 35 U.S.C. 120 i	pplication, U.S. Application		
The Ex	xamin nces w	er is requested to return a copy overe considered with the next offi	f the above list of pending ap ce communication.	plications indicating v	vhich
It is re	queste	ed that the information disclosed	herein be made of record in t	his application.	
Metho	d of p	ayment:			
[]	A ch the a	eck for the fee noted above is encompanying Reply. A copy of the	closed, or the fee has been inchis Statement is enclosed.	cluded in the check wi	th
[]		se charge Deposit Account 08-03 closed.	80 in the amount of \$[]. A copy of this State	ment
[X]	Pleas	se charge any deficiency in fees a	nd credit any overpayment to	Deposit Account 08-	0380
			Respectfully submitted,		
			HAMILTON, BROOK, SMI	TH & REYNOLDS, F	.C.
			By Charlton Shen Registration No.: 54,442 Telephone: (978) 341-0036 Facsimile: (978) 341-0136		

Concord, MA 01742-9133 Dated: 2 Feb. 2005

ATTORNEY DOCKET NO. 3194.1026-006 INFORMATION DISCLOSURE STATEMENT

EXAMINER

DT05 Rec'd PCT/PT0 0 APPLICATION NO.

FIRST NAMED INVENTOR Jeffrey J. Spiegelman FILING DATE

February 1, 2005

IN AN APPLICATION

(Use several sheets if necessary)

CONFIRMATION NO.

		U.S	S. PATENT DOCUMENTS	
EXAM- INER INI- TIAL	REF. NO.	DOCUMENT NUMBER Number-Kind Code (if known)	ISSUE DATE / PUBLICATION DATE MM-DD-YYYY	NAME OF PATENTEE OR APPLICANT OF CITED DOCUMENT
	AA	5,013,335	05-07-1991	Marcus
	AB	5,160,512	11-03-1992	Talu
	AC	5,230,721	07-27-1993	Ohmi
	AD	5,351,415	10-04-1994	Brooks et al.
	AF	5,540,757	07-30-1996	Jordan, Sr.
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EXAMINER	DATE CONSIDERED

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INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION

February 1, 2005

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ATTORNEY DOCKET NO. 3194.1026-006

EXAMINER

APPLICATION NO. 10/52337

FIRST NAMED INVENTOR

Jeffrey J. Spiegelman

FILING DATE

CONFIRMATION NO.

		U.S. P	UBLISHED APPLICATIONS	
EXAM- INER INI- TIAL	REF. NO.	DOCUMENT NUMBER Number-Kind Code (if known)	PUBLICATION DATE MM-DD-YYYY	NAME OF APPLICANT OF CITED DOCUMENT
	AI2	US2002/0018189 A1	02-14-2002	Mulkens et al.
	AJ2	2002088478	07-11-2002	Degendt et al.
	AK2	US2002/0192129A1	12-19-2002	Shamouilian et al.
	AA3	US2003/0096193 A1	05-22-2003	Van Schaik et al.
	AB3	20040238013	10/10/2003	Spiegelman et al.
	AC3	20040237777	10/10/2003	Alvarez et al.
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EXAMINER

FIRST NAMED INVENTOR
Jeffrey J. Spiegelman

FILING DATE

CONFIRMATION NO.

		F	OREIGN PATENT DO	DCUMENTS	
		DOCUMENT NUMBER Country Code-Number-Kind Code (if known)	DATE MM-DD-YYYY	NAME OF PATENTEE OR APPLICANT OF CITED DOCUMENT	TRANSLATION YES NO
	AL	WO 01/37329 A1	05-25-2001	Lucent Technologies, Inc.	
	AM	EP 0 867 924 A2	09-30-1998	Interuniversitair Micro- Elektronica Centrum VZW 3001 Heverlee (BE)	
	AM	DE 199 24 058 A1 (appended English Abstract Translation)	11-30-2000	Robert Bosch GmbH	
	AO				
	AP		2 00 20 00 00 00 200 200 00		
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ATTORNEY DOCKET NO. 3194.1026-006

EXAMINER

APPLICATION NO. 10/523

FIRST NAMED INVENTOR Jeffrey J. Spiegelman

FILING DATE

CONFIRMATION NO.

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)				
AR	Handbook of Semiconductor Wafer Cleaning Technology, Science, Technology, and Applications, Werner Kern Associates, eds., (NJ: Noyes Publications) pp. 88-89 (1993).			
AS	Veillerot, Marc, "A Method for Measuring AMC Concentrations Inside Wafer Containers," Materials Integrity Management Symposium 2003.			
АТ	Martin, Ray et al., "Status of Microenvironment Gas Purge in the Semiconductor Industry," Materials Integrity Management Symposium 2003.			
AU	Davidson, John, "The Expanding Role of Bare Reticle Stockers in Photolithography," Materials Integrity Management Symposium 2003.			
AV	Veillerot et al., "Organic Contamination: Purge Gas Impace in Plastic Storage Boxes," Solid State Phenomena, vol. 92, pp. 105-108 (2003).			
AW	Veillerot et al., "Testing the use of purge gas in wafer storage and transport containers," [online] 1997-2003 [retrieved 2004-11-10]. Retrieved from the Internet <url: 03="" 08="" archive="" http:="" td="" verllerot.html<="" www.micromagazine.com=""></url:>			
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